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DATE: Friday, October 27, 2006

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		<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>	
<input type="checkbox"/>	L10	L9 not l6	0
<input type="checkbox"/>	L9	L8 and viterbi with offset\$4 same standard deviation with (optimi\$7 or maximi\$7 or reduct\$3 or minim\$7)	1
<input type="checkbox"/>	L8	(714/791,792,794,795,796;375/262,265,341).ccls.	3507
		<i>DB=PGPB; PLUR=YES; OP=ADJ</i>	
<input type="checkbox"/>	L6	((("20040078748")!.PN.) .p145-p166.	1
		<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>	
<input type="checkbox"/>	L5	viterbi with offset\$4 same standard deviation with (optimi\$7 or maximi\$7 or reduct\$3 or minim\$7).clm.	1
<input type="checkbox"/>	L4	viterbi with offset\$4 same standard deviation with (optimi\$7 or maximi\$7 or reduct\$3 or minim\$7)	3
<input type="checkbox"/>	L3	L2 and @pd > 20060417	0
<input type="checkbox"/>	L2	('20040078748')!.ABPN1,NRPN,PN,TBAN,WKU.	2
<input type="checkbox"/>	L1	viterbi with offset\$4 same standard deviation	3

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## » Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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